
Identification cards — Test methods —

Part 6:

Proximity cards

AMENDMENT 3: Exchange of additional
parameters, block numbering, unmatched
AFI and TR2

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Cartes d'identification — Méthodes d'essai —

Partie 6: Cartes de proximité

*AMENDEMENT 3: Échange de paramètres additionnels, numérotation
des blocs, AFI non correspondant et TR2*

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The main task of the joint technical committee is to prepare International Standards. Draft International Standards adopted by the joint technical committee are circulated to national bodies for voting. Publication as an International Standard requires approval by at least 75 % of the national bodies casting a vote.

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Amendment 3 to ISO/IEC 10373-6:2011 was prepared by Joint Technical Committee ISO/IEC JTC 1, *Information technology*, Subcommittee SC 17, *Cards and personal identification*.

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Identification cards — Test methods —

Part 6: Proximity cards

AMENDMENT 3: Exchange of additional parameters, block numbering, unmatched AFI and TR2

Page 91, G.3.3.2.2

Add the following note after Table G.7:

NOTE The block number may be 0 or 1 dependent on block numbering rules defined in ISO/IEC 14443-4:2008, 7.5.3.

Page 116, G.4.4.1.2

Add the following note after Table G.38:

NOTE The block number may be 0 or 1 dependent on block numbering rules defined in ISO/IEC 14443-4:2008, 7.5.3.

Page 116, G.4.4.2.2

Add table footnote "e" to REQB and WUPB in Transition column of first and second rows in Table G.39.

Add table footnote "f" to REQB(Unmatched AFI) and WUPB(Unmatched AFI) in Transition column of tenth and eleventh rows in Table G.39.

Add table footnotes "e" and "f" in last row in Table G.39:

- e All matched AFIs as defined by the PICC manufacturer shall be tested.
- f The unmatched AFI used in this test shall not be an RFU value. If the PICC accepts all AFIs this test is not applicable.

Page 118, G.4.4.3.2

Add table footnote "e" to REQB and WUPB in Transition column of first and second rows in Table G.41.

Add table footnote "f" to REQB(Unmatched AFI) and WUPB(Unmatched AFI) in Transition column of twelfth and thirteenth rows in Table G.41.

Add table footnotes "e" and "f" in last row in Table G.41:

- e All matched AFIs as defined by the PICC manufacturer shall be tested.
- f The unmatched AFI used in this test shall not be an RFU value. If the PICC accepts all AFIs this test is not applicable.

Page 119, G.4.4.4.2

Add table footnote “e” to REQB and WUPB in Transition column of first and second rows in Table G.43.

Add table footnote “f” to REQB(Unmatched AFI) and WUPB(Unmatched AFI) in Transition column of fourteenth and fifteenth rows in Table G.43.

Add table footnotes “e” and “f” in last row in Table G.43:

- e All matched AFIs as defined by the PICC manufacturer shall be tested.
- f The unmatched AFI used in this test shall not be an RFU value. If the PICC accepts all AFIs this test is not applicable.

Page 121, G.4.4.5.2

Add table footnote “d” to REQB and WUPB in Transition column of first and second rows in Table G.45.

Add table footnote “e” to REQB(Unmatched AFI) and WUPB(Unmatched AFI) in Transition column of ninth and tenth rows in Table G.45.

Add table footnotes “d” and “e” in last row in Table G.45:

- d All matched AFIs as defined by the PICC manufacturer shall be tested.
- e The unmatched AFI used in this test shall not be an RFU value. If the PICC accepts all AFIs this test is not applicable.

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Page 123, G.4.4.6.2

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Add table footnote “b” to REQB and WUPB in Transition column of first and second rows in Table G.47.

Add table footnote “c” to WUPB(Unmatched AFI) and REQB(Unmatched AFI) in Transition column of tenth and eleventh rows in Table G.47.

Add table footnotes “b” and “c” in last row in Table G.47:

- b All matched AFIs as defined by the PICC manufacturer shall be tested.
- c The unmatched AFI used in this test shall not be an RFU value. If the PICC accepts all AFIs this test is not applicable.

Page 142, G.5.4.2

Add the following new Scenario after Scenario G.62:

Scenario G.66: CID on S(PARAMETERS)-block

Step	PICC-test-apparatus	PICC
1	S(PARAMETERS, CID = cid _{cmd})	<p style="text-align: center;">→</p> <p style="text-align: center;">←</p> <p style="text-align: center;">Response 1: S(PARAMETERS, CID = cid_{cmd}) Response 2: Mute ^a</p>
^a	Response 1 or response 2 according to Table G.55 or Table G.56.	

Page 143, after G.5.5.3

Add the following new clauses at the end of G.5.5.3:

G.5.6 PICC reaction on S(PARAMETERS) blocks

G.5.6.1 Scope

This test is to determine the behavior of the PICC according to ISO/IEC 14443-4:2008/Amd.1:2012, 7.5.1. This test uses implementations of the protocol Scenarios of ISO/IEC 14443-4:2008/Amd.1:2012, Annex B.2.6.

G.5.6.2 Procedure

Perform the following steps for each of Scenario G.67 through G.70 listed in this subclause:

- a) Activate the PICC as described in G.5.1.1, use CID = 0 and FSDI = 0.
- b) For each step in the Scenario do:
 - 1) Send the command as described in the PICC-test-apparatus column.
 - 2) Check that the PICC response matches the one of the PICC column.
- c) End for.

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Scenario G.67: Exchange of additional parameters

Step	PICC-test-apparatus		PICC
1	I(0) ₀ (TEST_COMMAND1(1))	→	I(0) ₀ (TEST_RESPONSE1(1))
2	S(PARAMETERS)	→	S(PARAMETERS)
3	I(0) ₁ (TEST_COMMAND1(1))	→	I(0) ₁ (TEST_RESPONSE1(1))

Scenario G.68: Exchange of additional parameters

Step	PICC-test-apparatus		PICC
1	S(PARAMETERS)	→	S(PARAMETERS)
2	I(0) ₀ (TEST_COMMAND1(1))	→	I(0) ₀ (TEST_RESPONSE1(1))

Scenario G.69: Exchange of additional parameters

Step	PICC-test-apparatus		PICC
1	S(PARAMETERS)	→	
		←	S(PARAMETERS)
2	S(PARAMETERS)	→	
		←	S(PARAMETERS)
3	I(0) _o (TEST_COMMAND1(1))	→	
		←	I(0) _o (TEST_RESPONSE1(1))

Scenario G.70: Exchange of additional parameters

Step	PICC-test-apparatus		PICC
1	S(PARAMETERS, ~CRC)	→	
		←	Mute
2	S(PARAMETERS)	→	
		←	S(PARAMETERS)
3	I(0) _o (TEST_COMMAND1(1))	→	
		←	I(0) _o (TEST_RESPONSE1(1))

G.5.6.3 Test report

Fill the appropriate rows in Table G.63 according to Table Amd.3-1.

Table Amd.3-1 — Result criteria for exchange of additional parameters

Explanation	Test result
Only when the PICC responded as indicated in the procedure	PASS
Any other case	FAIL

Page 144, G.6

Remove Line No 10 of Table G.60 referring to parameter TR2.

Page 146, G.6

Insert new Scenarios G.66 to G.70 in Table G.63 as follows:

Test method from ISO/IEC 10373-6		Scenario numbers	Test result
Clause	Parameter	ISO/IEC 10373-6	PASS or FAIL or N/A
G.5.4	PICC reaction on CID	Scenario G.58	
		Scenario G.59	
		Scenario G.60	
		Scenario G.61	
		Scenario G.62	
		Scenario G.66	
G.5.6	PICC reaction on S(PARAMETERS) blocks	Scenario G.67	
		Scenario G.68	
		Scenario G.69	
		Scenario G.70	

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Page 181, H.4.3.2.12

Add the following note in H.4.3.2.12 after Step h). <http://standards.iteh.ai/catalog/standards/sist/cd176843-6745-487b-bb0a-03b1c7aa0264/iso-iec-10373-6-2011-amd-3-2012>

NOTE Within this scenario the new rule 8 is tested only for S(DESELECT) blocks.

Page 183, H.5.4

Replace the content of H.5.4 with the following:

S-block shall have either

- an INF field of one byte only when it is a WTX block, or
- an INF field of n byte(s) ($n \geq 0$) when it is a PARAMETERS block, or
- no INF field otherwise.

(see ISO/IEC 14443-4:2008, 7.1.1.1 and ISO/IEC 14443-4:2008/Amd.1).